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- ☐ 1. **Enhancing the performance of multi-cycle path analysis in an industrial setting**
 Higuchi, H.; Matsunaga, Y.;
Design Automation Conference, 2004. Proceedings of the ASP-DAC 2004. Asia and South Pacific
 27-30 Jan. 2004 Page(s):192 - 197
[AbstractPlus](#) | Full Text: [PDF\(467 KB\)](#) IEEE CNF
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- ☐ 2. **An implication-based method to detect multi-cycle paths in large sequential circuits**
 Higuchi, H.;
Design Automation Conference, 2002. Proceedings. 39th
 10-14 June 2002 Page(s):164 - 169
 Digital Object Identifier 10.1109/DAC.2002.1012613
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